## Supporting information

## Improving BiVO<sub>4</sub> photoanodes for solar water splitting through surface passivation

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1. The mirror will only cause a distortion (enriching of the NIR part) of the simulated sunlight spectrum.



**Figure S1**. The reflection spectrum of the UV-enhanced mirror, which is used for flipping the simulated sunlight. (model PAUV-PM-5010M-C, provided by Melles Griot)

Compared with the AM1.5 sunlight, the actual light hitting  $BiVO_4$  is slightly enriched by the NIR photons due to the high reflectance in NIR region for the mirror. The net result is ~10% less photons (wavelength between 300 nm and 600 nm) will be available. Since  $BiVO_4$  can not absorb the NIR light (>800nm), a slightly smaller photocurrent for  $BiVO_4$  photoelectrodes than that under a real AM1.5 sunlight.

2. Without loading the  $NiO_x$ , the characterization of  $BiVO_4$  films either in phosphate or in borate electrolyte does not passivate the electrode.



**Figure S2.** (A) CVs of an as-prepared  $BiVO_4$  film electrode in 0.2M NaP*i*. (B) CVs of an the same  $BiVO_4$  film electrode in 0.2M NaB*i*. Bothe the dark current and photocurrent under white light illumination are shown.

Figure S2 shows that exposure of  $BiVO_4$  to the phosphate electrolyte or borate electrolyte will give very repeatable *low* photocurrent during 4 cycles of electrochemical sweeping between  $0.3V_{RHE}$  and  $1.8V_{RHE}$ . The anomalies in current during the 1<sup>st</sup> CV cycle are due to the fact that the starting potential is not from the open circuit potential.

3. The BiVO<sub>4</sub> film only absorbs ~90% of the photons of wavelength from 300 nm to 600 nm.



Figure S3. The light absorption spectrum of the BiVO<sub>4</sub> film electrode.

The BiVO<sub>4</sub> film only absorbs ~90% of the photons at the plateau of the UV-vis absorption spectrum. This will cause the measured photocurrent lower than the value if all the photons can be absorbed by the film electrodes.



4. The control experiments demonstrate that the  $NiO_x$  films on FTO can be removed in phosphate electrolyte.

**Figure S4**. (A) CV of blank FTO substrate in NaB<sub>i</sub> electrolyte. (B) the CV for loading of NiO<sub>x</sub> onto FTO substrate in Ni<sup>2+</sup> containing NaB<sub>i</sub> electrolyte. (C) CV for the removal of NiO<sub>x</sub> from FTO substrate in NaP<sub>i</sub> electrolyte

From Figure S4, it can be clearly seen that  $NiO_x$  can be loaded in borate buffered electrolyte, and can be removed in phosphate containing electrolyte.





**Figure S5**. (A) XPS spectra of the Bi V for as-prepared BiVO<sub>4</sub> electrode, (B) XPS spectra of Ni, Bi and V for the BiVO<sub>4</sub> film right after NiO<sub>x</sub> loading, (C) XPS spectra of Ni, Bi and V for the BiVO<sub>4</sub> film right after treating NiO<sub>x</sub>-loaded film in phosphate electrolyte. The spectra are fitted and the composition is quantified and summarized in Table 1 in the main text.

## 6. The photocurrent from BiVO<sub>4</sub> is not due to the photoetching of BiVO<sub>4</sub>

For a BiVO<sub>4</sub> film (100nm thick) working at ~1 mA/cm<sup>2</sup> for 20min, a rough estimation shows that the electrons pass through will be ~8.1 time the amount of Oxygen from BiVO4. This safely excludes the possibility that the photocurrent (~1.5 mA/cm<sup>2</sup> for ~1h) shown in the maintext can be due to the photoetching of BiVO<sub>4</sub>.

$$\frac{N_{electron}}{N_{oxygen} \times 2} = \frac{\frac{1mA/cm^2 * 1200 \sec onds}{96485}}{\frac{100 * 10^{-7} cm * 6.2g/cm^2}{209 + 50.9 + 64}} = 8.1$$

7. sulfite adding significantly increases the photocurrents by increasing the hole transfer rate, and makes the passivation effect less-observable for  $BiVO_4$  photoelectrode



**Figure S7**. CVs under the AM 1.5 illumination for another BiVO<sub>4</sub> electrode treated at different stages, (black) as-prepared BiVO<sub>4</sub> film, (green) BiVO<sub>4</sub> film after electrochemical loading of NiO<sub>x</sub>, and (red) BiVO<sub>4</sub> film after removal of NiO<sub>x</sub> OER center. (A) in 0.2M NaB<sub>i</sub> (B) in 0.1M NaB<sub>i</sub> + 0.05M Na<sub>2</sub>SO<sub>3</sub>.

After adding sulfite, there is only a minor change after  $NiO_x$  loading and no observable change when  $NiO_x$  OER center is removed (Figure S7B). It can be clearly seen that sulfite adding significantly increases the photocurrent, which is a result of the increased hole transfer rate. The hole transfer process get so much facilitated for sulfite containing electrolyte that the effect resulted from passivation (after removal of NiO<sub>x</sub> OER center) is almost not observable.